



Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09601540	TOMANEK ET AL.
	Examiner Brittain, James R	Art Unit 3677

Notes	Date	Examiner
STIC search for corresponding international application and for this application	05/17/1999	JRB
PLUS search	10/23/2001	JRB
EAST text search	10/24/2000, 10/25/2000, 10/23/2001, 2/14/2002, 8/27-8/30/2002	JRB
Consulted D. S. Nakurani in class 428; S. Henderson in cl. 423; M. Mayes in cl. 156	08/28/2002	JRB
EAST text search continued	1/6/2003, 12/15/2003, 2/14/2004, 3/31/2004, 8/12/2005, 8/22/2005	JRB
Forward and backward search performed on US 5464987	08/14/2006	JRB
U.S. Patent and Trademark Office		Part of Paper No.: 20060816

Interference Searched 	Application/Control No. 09601540	Applicant(s)/Patent Under Reexamination TOMANEK ET AL.
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Class	SubClass	Date	Examiner
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Searched 	Application/Control No. 09601540	Applicant(s)/Patent Under Reexamination TOMANEK ET AL.
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Class	SubClass	Date	Examiner
24	442, 444, 446-452	03/05/2002	JRB
423	447.1		
428	420, 100		
updated above		08/28/2002	JRB
428	402, 408		
423	447.2		
156	272.2, 297, 274.4		
updated above		03/31/2004	JRB
977	dig. 1	02/03/2005	JRB
updated above		08/12/2005	JRB
428	99, 119, 120	10/25/2005	JRB
updated above		08/14/2006	JRB
977	724, 732, 882	08/16/2006	JRB
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